

General Description

This Legacy device is a JEDEC standard unbuffered SO-DIMM module, based on CMOS DDR4 SDRAM technology, and is available as a 2048Mx64 (16GB). This device consists of 16 CMOS DDR4 SDRAMs in FBGA packages on a 260-pin glass epoxy substrate.

The memory array is designed with Double Data Rate (DDR4) Synchronous DRAMs for unbuffered applications. The pipelined, multibanked architecture of DDR4 SDRAMs allows for concurrent operation, thereby providing high, effective bandwidth. Decoupling capacitors are mounted on the PCB board in parallel for each DDR4 SDRAM, which provides proper voltage supply impedance over the whole frequency range of operations, in accordance with JEDEC specifications.

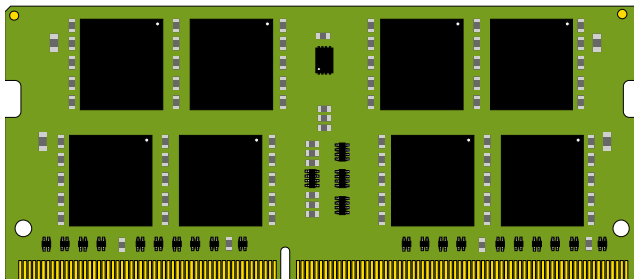
These modules feature Serial Presence Detect (SPD) based on a serial EEPROM device, using the 2-pin I2C protocol. The first 383 bytes are programmed with configuration data and the second 127 bytes are available to the customer.

Legacy Electronics offers a wide range of products featuring industry leading compatibility, manufactured to the highest quality standards and made entirely in America.

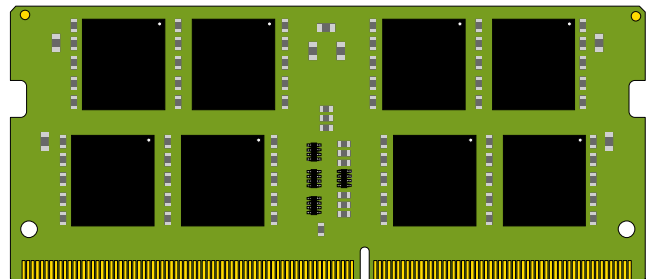
Features

- 260-pin Unbuffered 8-Byte DDR4 SDRAM Memory Module for PC and Workstation main memory applications
- Assembled using: 1024Mx8 components
- Dual rank organization 2048Mx64
- JEDEC standard 1.2V I/O
- VDD = +1.2V ± 0.06V, VPP = +2.5V TYP
- 16 internal banks; 4 groups of 4 banks each
- RESET pin for improved system stability
- Differential clock inputs (CK, CK#)
- Multiplexed command and address bus
- Fixed burst length of 8 (BL8) and burst chop of 4 (BC4) via the mode register set
- Adjustable data output drive strength
- Terminated command, address, and control bus
- On-die V_{REF}DQ generation and calibration
- TOPER operating Temperature -40°C ~ 85°C
- Serial Presence Detect (SPD) with EEPROM
- Impedance controlled 8-layer PCB Technology
- JEDEC standard form factor (69.6 mm x 30.0 mm)
- JEDEC DDR4 Raw Card E1
- RoHS Compliant

Front View



Back View



Part Number and Timing Parameters

Part Numbers	Modules Density	Configuration	Module Bandwidth	Memory Clock/ Data Rate	Latency (CL-tRCD-tRP)
LE4ASS21PEH-ME100-00100	16GB	2048Mx64	17.0 GB/s	0.93ns/2133 MT/s	15-15-15
All part numbers with a (-XXXXXX) Designate DRAM die revision and option codes					

Address Table

Parameters	16GB Density
Refresh Count	8K
Row Addressing	32K (A0 ~ A14)
Device Bank Addressing	16 (BA0 ~ BA1)(BG0 ~ BG1)
Device Configuration	8GB(1024Mx8)
Column Addressing	1K (A0 ~ A9)
Module Rank Addressing	2 (S0#, S1#)

Pin Assignments

260-Pin SO-DIMM Pins FRONT								260-Pin SO-DIMM Pins BACK							
PIN	SYMBOL	PIN	SYMBOL	PIN	SYMBOL	PIN	SYMBOL	PIN	SYMBOL	PIN	SYMBOL	PIN	SYMBOL	PIN	SYMBOL
1	VSS	67	DQ29	133	A1	199	DM5/ DBI5#	2	VSS	68	VSS	134	EVENT# (NC)	200	DQS5
3	DQ5	69	VSS	135	VDD	201	VSS	4	DQ4	70	DQ24	136	VDD	202	VSS
5	VSS	71	DQ25	137	CK0	203	DQ46	6	VSS	72	VSS	138	CK1#	204	DQ47
7	DQ1	73	VSS	139	CK0#	205	VSS	8	DQ0	74	DQS3#	140	CK1	206	VSS
9	VSS	75	DM3/DBI3	141	VDD	207	DQ42	10	VSS	76	DQS3	142	VDD	208	DQ43
11	DQS0#	77	VSS	143	PARITY	209	VSS	12	DM0/ DBI0#	78	VSS	144	A0	210	VSS
13	DQS0	79	DQ30	145	BA1	211	DQ52	14	VSS	80	DQ31	146	A10/AP	212	DQ53
15	VSS	81	VSS	147	VDD	213	VSS	16	DQ6	82	VSS	148	VDD	214	VSS
17	DQ7	83	DQ26	149	S0	215	DQ49	18	VSS	84	DQ27	150	BA0	216	DQ48
19	VSS	85	VSS	151	A14/WE#	217	VSS	20	DQ2	86	VSS	152	A16/RAS#	218	VSS
21	DQ3	87	CB5	153	VDD	219	DQS6#	22	VSS	88	CB4	154	VDD	220	DM6/ DBI6#
23	VSS	89	VSS	155	ODT0	221	DQS6	24	DQ12	90	VSS	156	A15/CAS#	222	VSS
25	DQ13	91	CB1	157	S1#	223	VSS	26	VSS	92	CB0	158	A13	224	DQ54
27	VSS	93	VSS	159	VDD	225	DQ55	28	DQ8	94	VSS	160	VDD	226	VSS
29	DQ9	95	DQS8#	161	ODT1	227	VSS	30	VSS	96	NC (DBI8#)	162	C0 S2# (NC)	228	DQ50
31	VSS	97	DQS8	163	VDD	229	DQ51	32	DQS1#	98	VSS	164	VREFCA	230	VSS
33	DM1/DBI1	99	VSS	165	C1 S3# (NC)	231	VSS	34	DQS1	100	CB6	166	SA2	232	DQ60
35	VSS	101	CB2	167	VSS	233	DQ61	36	VSS	102	VSS	168	VSS	234	VSS
37	DQ15	103	VSS	169	DQ37	235	VSS	38	DQ14	104	CB7	170	DQ36	236	DQ57
39	VSS	105	CB3	171	VSS	237	DQ56	40	VSS	106	VSS	172	VSS	238	VSS
41	DQ10	107	VSS	173	DQ33	239	VSS	42	DQ11	108	RESET#	174	DQ32	240	DQS7#
43	VSS	109	CKE0	175	VSS	241	DM7/ DBI7#	44	VSS	110	CKE1	176	VSS	242	DQS7
45	DQ21	111	VDD	177	DQS4#	243	VSS	46	DQ20	112	VDD	178	DM4/ DBI4#	244	VSS
47	VSS	113	BG1	179	DQS4	245	DQ62	48	VSS	114	ACT#	180	VSS	246	DQ63
49	DQ17	115	BG0	181	VSS	247	VSS	50	DQ16	116	ALERT#	182	DQ39	248	VSS
51	VSS	117	VDD	183	DQ38	249	DQ58	52	VSS	118	VDD	184	VSS	250	DQ59
53	DQS2#	119	A12	185	VSS	251	VSS	54	DM2/ DBI2#	120	A11	186	DQ35	252	VSS
55	DQS2	121	A9	187	DQ34	253	SCL	56	VSS	122	A7	188	VSS	254	SDA
57	VSS	123	VDD	189	VSS	255	VDDSPD	58	DQ22	124	VDD	190	DQ45	256	SA0
59	DQ23	125	A8	191	DQ44	257	VPP	60	VSS	126	A5	192	VSS	258	VTT
61	VSS	127	A6	193	VSS	259	VPP	62	DQ18	128	A4	194	DQ41	260	SA1
63	DQ19	129	VDD	195	DQ40	-	-	64	VSS	130	VDD	196	VSS	-	-
65	VSS	131	A3	197	VSS	-	-	66	DQ28	132	A2	198	DQS5#	-	-

Pin Descriptions

SYMBOL	TYPE	FUNCTION
CK0 ~ CK0# CK1 ~ CK1#	Input	Clock: CK, CK# are differential clock inputs. All the DDR4 SDRAM address and control inputs are sampled on the crossing of positive edge of CK and negative edge of CK#. Output (read) data is reference to the crossing of CK and CK# (Both directions of crossing).
CKE0, CEK1	Input	Clock Enable: Activates the SDRAM CK signal when high and deactivates the CK signal when low. By deactivating the clocks, CEK low initiates the Power Down mode, or the Self Refresh mode.
S0#,	Input	Chip Select: Enables the associated SDRAM command decoder when low and disables the command decoder when high. When the command decoder is disabled, new commands are ignored but previous operations continue. This signal provides for external rank selection on systems with multiple ranks.
RAS#, CAS#, WE#	Input	Command Inputs: RAS#, CAS#, and WE# (S# as well) define the command being entered.
RESET#	Input	Reset: An active LOW CMOS input referenced to VSS and not referenced to VREFCA or VREFDQ. The reset pin input receiver is a CMOS input and is defined as a rail-to-rail signal with a DC HIGH $\geq 0.8 \times VDDQ$ and DC LOW $\leq 0.2 \times VDDQ$ (1.20V for HIGH and 0.30V for LOW). RESET# assertion and desertion are asynchronous. System applications will most likely be unterminated, heavily loaded, and have very slow slew rates. A slow slew rate receiver design is recommended along with implementing on-chip noise filtering to prevent false triggering (RESET# assertion minimum pulse width is 100ns).
ODT0 ~ ODT1	Input	On-Die Termination: ODT (registered HIGH) enables termination resistance internal to the DDR4 SDRAM. When enabled, ODT is only applied to each of the following pins: DQ, DQS, DQS#, and DM. The ODT input will be ignored if disabled via the LOAD MODE command.
BA0 ~ BA1	Input	Bank Address: BA0, BA1, and BA2 define to which device bank an ACTIVE, READ, WRITE, or PRE-CHARGE command is applied.
A0 ~ A17	Input	Address Inputs: During a Bank Activate command cycle, Address input defines the row address (RA0 ~ RA15). During a Read or Write command cycle, Address input defines the column address. In addition to the column address, AP is used to invoke auto precharge operation at the end of the burst read or write cycle. If AP is high, auto precharge is selected and BA0, BA1, BA2 defines the bank to be precharged. If AP is low, auto precharge is disabled. During a precharge command cycle, AP is used in conjunction with BA0, BA1, BA2 to control which bank(s) to precharge. If AP is high, all banks will be precharged regardless of the state of BA0, BA1 or BA2. If AP is low, BA0, BA1 and BA2 are used to define which bank to precharge. A12(BC) is sampled during READ and WRITE commands to determine if burst chop (on-the-fly) will be performed (HIGH, no burst chop; LOW, burst chopped).
ACT#	Input	Activation Command Input: ACT_n defines the Activation command being entered along with CS#. The input into RAS#/A16, CAS#/A15 and WE#/A14 will be considered as Row Address A16, A15 and A14.
A10 / AP	Input	Auto-precharge: A10 is sampled during Read/Write commands to determine whether Autoprecharge should be performed to the accessed bank after the Read/Write operation. (HIGH: Autoprecharge; LOW: no Autoprecharge). A10 is sampled during a Precharge command to determine whether the Precharge applies to one bank (A10 LOW) or all banks (A10 HIGH). If only one bank is to be precharged, the bank is selected by bank addresses.
A12 / BC#	Input	Burst Chop: A12/BC_n is sampled during Read and Write commands to determine if burst chop (on-the-fly) will be performed. (HIGH, no burst chop; LOW: burst chopped). See command truth table for details.
BG0, BG1	Input	Bank Group Inputs: BG0 - BG1 define which bank group an Active, Read, Write or Precharge command is being applied. BG0 also determines which mode register is to be accessed during a MRS cycle. x4/x8 SDRAM configurations have BG0 and BG1. x16 based SDRAMs only have BG0.
DQS0 ~ DQS17 DQS0# ~ DQS17#	Input / Output	Data Strobe: Output with READ data, input with WRITE data. DQS is edge-aligned with READ data and is centered in WRITE data. Used to capture data.
DQ0 ~ DQ63	Input / Output	Data I/Os: Bidirectional Data bus.
ALERT#	Output	Alert: It has multi functions such as CRC error flag, Command and Address Parity error flag as Output signal. If there is error in CRC, then ALERT# goes LOW for the period time interval and goes back HIGH. If there is error in Command Address Parity Check, then ALERT_n goes LOW for relatively long period until on going DRAM internal recovery transaction is complete. During Connectivity Test mode this pin functions as an input.

Pin Descriptions

SYMBOL	TYPE	FUNCTION
Parity	Input	Command and Address Parity Input: DDR4 Supports Even Parity check in DRAMs with MR setting. Once it's enabled via Register in MR5, then DRAM calculates Parity with ACT#, RAS#/A16, CAS#/A15, WE#/A14, BG0-BG1, BA0-BA1, A16-A0. Input parity should be maintained at the rising edge of the clock and at the same time with command & address with CS# LOW
ZQ	Supply	Reference Pin for ZQ calibration
V _{DD}	Supply	Power supply: +1.5V (±0.075V) or 1.35V (1.283V to 1.45V) for low voltage modules.
V _{TT}	Supply	Termination Voltage: Used for address, command, control, and clock nets. V _{DD} /2
V _{DDSPD}	Supply	Power supply: Serial EEPROM positive power supply, 3.3V (3.0V to 3.6V).
V _{REFDQ}	Supply	Reference Voltage: DQ and DM. V _{DD} /2
V _{REFCA}	Supply	Reference Voltage: Command, address, and control. V _{DD} /2
V _{SS}	Supply	Ground.
SDA	Input / Output	Serial Presence-Detect Data: SDA is a bidirectional pin used to transfer addresses and data into and out of the presence-detect portion of the module.
SCL	Input / Output	SCL Input Serial Clock for Presence-Detect: SCL is used to synchronize the presence-detect data transfer to and from the module.
SA0 ~ SA2	Input	SA0 ~ SA2 Input SPD Address Inputs: These pins are used to configure the presence-detect device.
NC	-	No Connect: These pins should be left unconnected.
RFU	-	Reserved for future use: No on DIMM electrical connection is present

Absolute Maximum DC Ratings

Parameters ¹	Symbol	MIN	MAX	Unit
Voltage on any pin relative to V _{SS}	V _{IN} , V _{OUT}	-0.4	1.5	V
Voltage on V _{DD} supply relative to V _{SS}	V _{DD}	-0.4	1.5	V
Voltage on V _{DDQ} supply relative to V _{SS}	V _{DD}	-0.4	1.5	V
Storage Temperature	T _{STG}	-55	100	°C

¹ Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Operating Temperature Range

Parameters	Symbol	MIN	MAX	Unit
DIMM Module Operating Temperature Range (ambient)	T _{OPR} ¹	-40	85	°C
DRAM Component Case Temperature Range	T _{OPR} ¹	-25	95	°C

¹ Operating Temperature T_{OPR} is the case surface temperature on the center/top side of the DRAM. For measurement conditions, please refer to the JEDEC document JESD51-2.

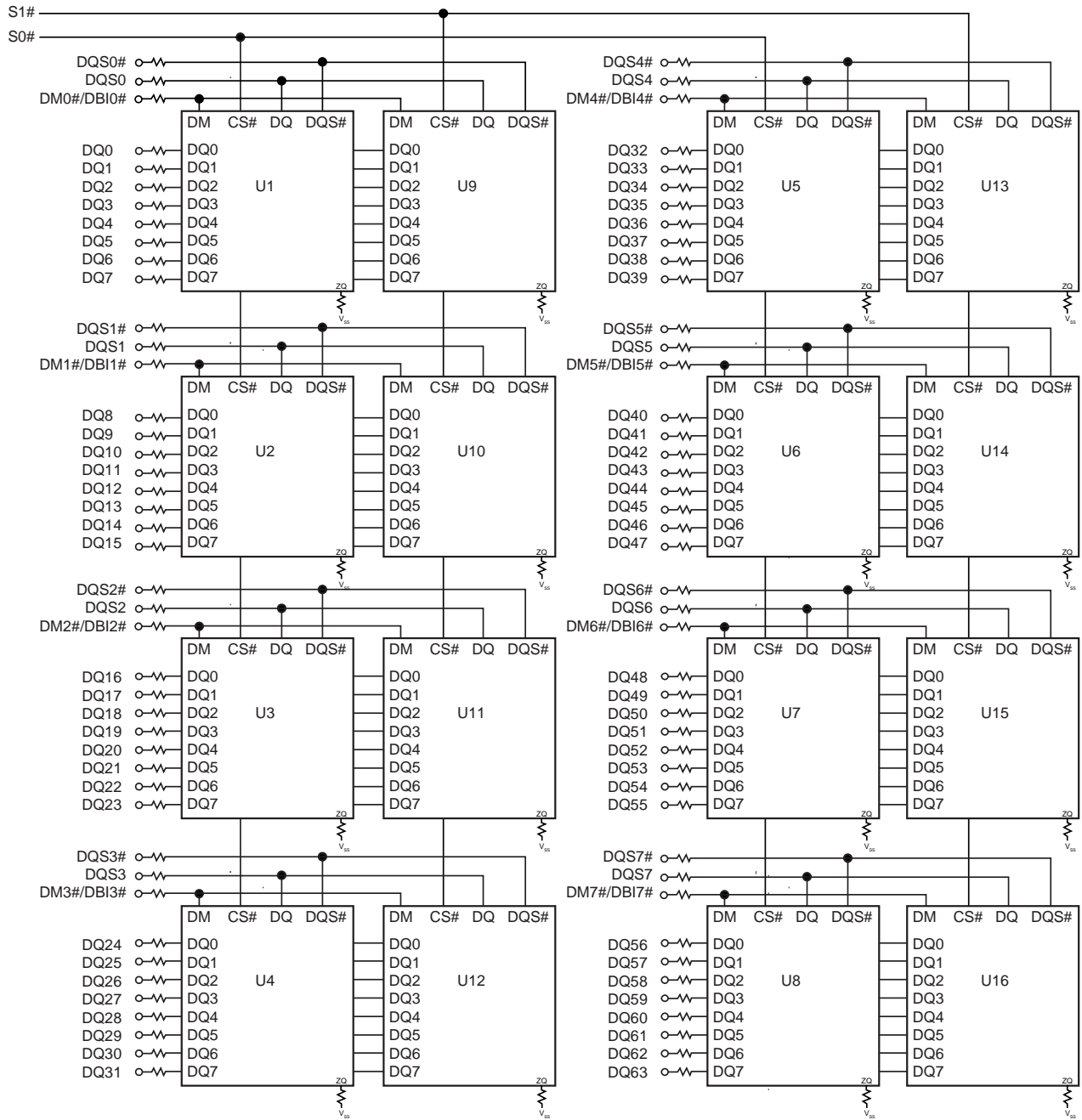
² The Normal Temperature Range specifies the temperatures where all DRAM specifications will be supported. During operation, the DRAM case temperature must be maintained between 0 ± 70°C under all operating conditions. For Industrial Temperature DRAM case temperature must be maintained between -25 ± 95°C under all operating conditions.

AC & DC Operating Conditions

Parameters	Symbol	MIN	NOM	MAX
Supply Voltage	V _{DD}	1.14 V	1.2 V	1.26 V
DRAM activating power supply	V _{PP}	2.375 V	2.5 V	2.75 V
I/O Supply Voltage ¹	V _{DDQ}	1.14 V	1.2 V	1.26 V
SPD Supply Voltage	V _{DDSPD}	2.5 V	3.3 V	-

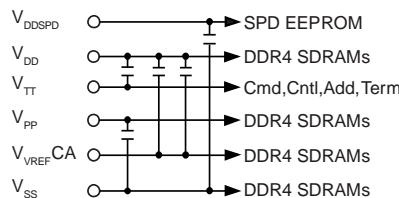
¹ Under all conditions VDDQ must be less than or equal to VDD.

Functional Block Diagram

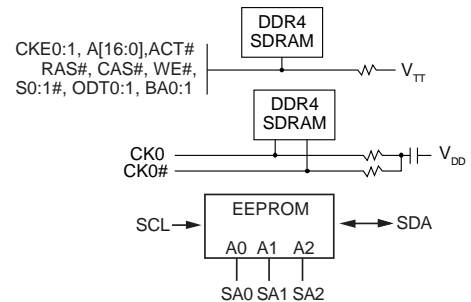


- BA0-BA1 → BA0-BA1: DDR4 SDRAMs
- A0-A16 → A0-A16: DDR4 SDRAMs
- RAS# → RAS#: DDR4 SDRAMs
- CAS# → CAS#: DDR4 SDRAMs
- WE# → WE#: DDR4 SDRAMs
- RESET# → RESET#: DDR4 SDRAMs
- ALERT# → ALERT#: DDR4 SDRAMs
- ACT# → ACT#: DDR4 SDRAMs
- PARITY → PARITY: DDR4 SDRAMs
- BG0-BG1 → BG0-BG1: DDR4 SDRAMs
- CKE0 → CKE0: DDR4 SDRAMs
- ODT0 → ODT0: DDR4 SDRAMs

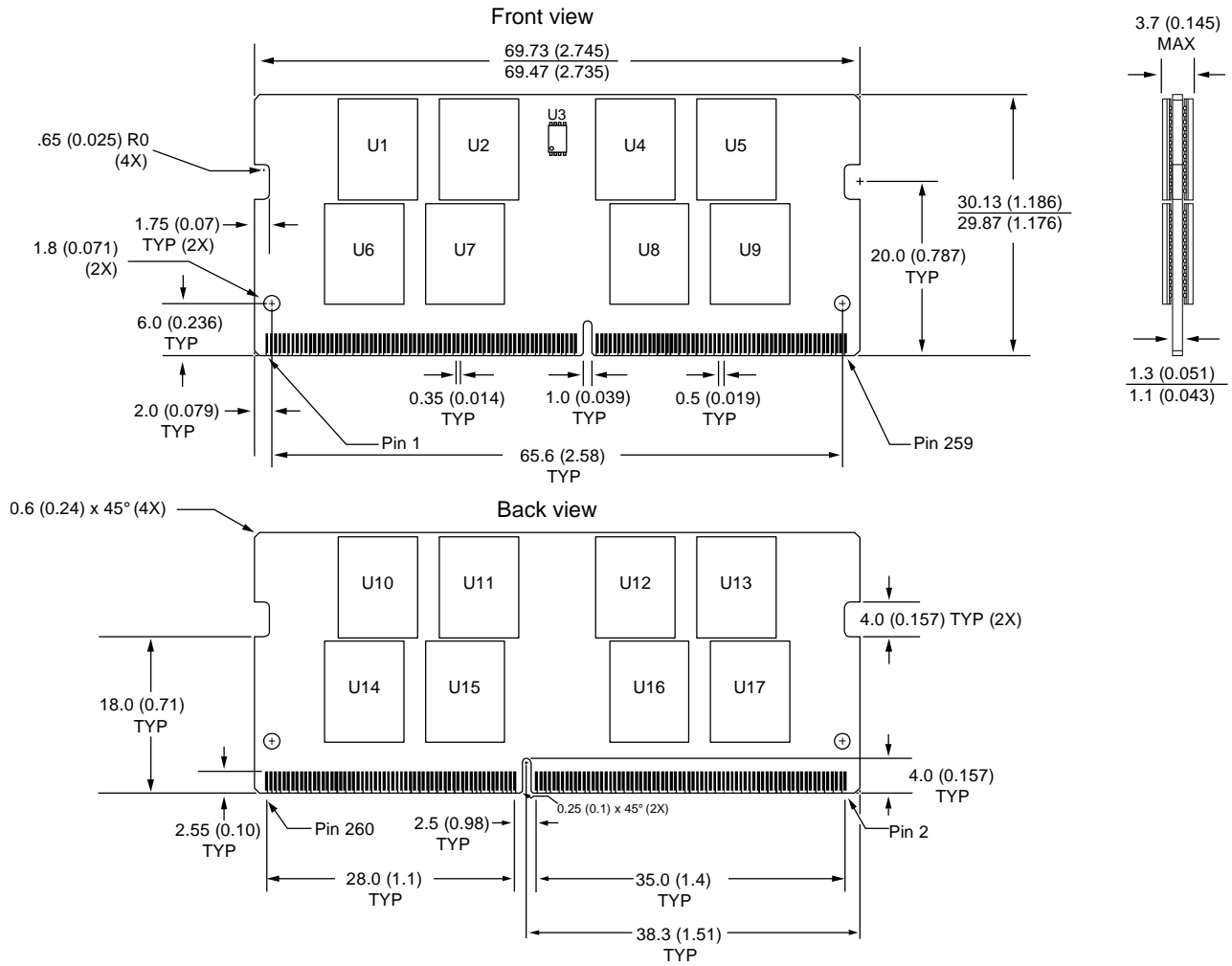
- CK0 → DDR4 SDRAMs
- CK0# → DDR4 SDRAMs
- CK1 → DDR4 SDRAMs
- CK1# → DDR4 SDRAMs



Address, command, control, and clock line terminations:



Module Dimensions



About Us

Located in Canton, South Dakota, Legacy Electronics specializes in designing and manufacturing a full line of high-density memory modules, printed circuit boards, SSDs, and other computer products.

Legacy Electronics is home of the patented Canopy® chip-stacking alternative, a three-dimensional printed circuit board subassembly and process technology. Legacy utilizes an ISO 9001:2008 certified Quality Management System.

Legacy's cutting edge products are available in a variety of densities, speeds, and voltage levels. Our standard and custom modules are available in a wide array of form factors, including JEDEC-standard DIMMs and SO-DIMMs. Our products exceed industry standards. All Legacy products are proudly made in the USA..

Advanced tested memory products

Legacy Electronics is the only company to have a 100% pass rate for over 300 tests in a calendar year at CMTL (Computer Memory Test Labs).

In addition, CMTL awarded Legacy Electronics with a lifetime achievement award after 15 plus years of service with CMTL.

The CMTL Memory Module Certification Program performs advanced compatibility testing on motherboards from the industry's leading manufacturers like Intel®. All the modules listed at CMTL have passed rigorous cross platform certification testing criteria and are proven to be compatible with the motherboards on which they were tested.



Contact Us

Give us a call or visit us online for more information about our products and services.

Phone:

(605) 558-9600

Fax:

(605) 271-4780

Legacy Electronics Inc.
1220 North Dakota Street
PO Box 348
Canton, SD 57013

Visit us on the web at:
www.legacyelectronics.com

Email sales at:
sales@legacyelectronics.com